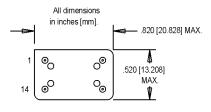
K1524A Series 14 DIP, 5.0 Volt, CMOS/TTL, VCXO

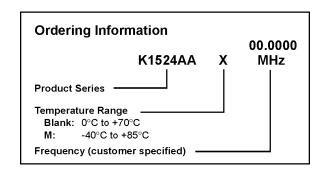


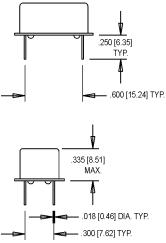


• Former Champion Product

 Phase-Locked Loops (PLL's), Clock Recovery, Reference Signal Tracking, Synthesizers, Frequency Modulation/ Demodulation







Pin Connections

PIN	FUNCTION				
1	Voltage Control				
7	Ground/Case Ground				
8	Output				
14	+Vdd				

	PARAMETER	Symbol	Min.	Тур.	Max.	Units	Condition
	Frequency Range	F	3		35	MHz	
	Frequency Stability:	∆F/F					
	Overall	1	Inclusive	of Calibra	tion. Tempe	rature.	
			Inclusive of Calibration, Temperature, Voltage, Load, and Aging				
	0°C to +70°C				±50	ppm	
	-40°C to +85°C				±70	ppm	
	Pullability		±300		±525	ppm	
	Linearity				15	%	
suc	Modulation Bandwidth	fm	>20			kHz	±3dB
atio	Control Voltage	Vc	0.5	2.5	4.5	ν	
iiic	Transfer Function		Positive				
Electrical Specifications	Input Impedance		>50 K Ω				@ 10 kHz
al S	Operating Temperature	TA	-40		+85	°C	
tric	Storage Temperature	Ts	-40		+125	°C	
ec	Input Voltage	Vdd	4.75	5.0	5.25	٧	
"	Input Current	ldd			26	mA	
	Symmetry (Duty Cycle)		40		60	%	@ 50% Vdd
	Rise Time (TTL)	Tr			4	ns	20% to 80% Vdd
	Rise Time (CMOS)	Tr			5	ns	20% to 80% Vdd, CL=15pF
	Fall Time (TTL)	Tf			4	ns	80% to 20% Vdd
	Fall Time (CMOS)	Tf			4	ns	80% to 20% Vdd, CL=15pF
	Logic "1" Level	Voh	Vdd-0.5			٧	
	Logic "0" Level	Vol			0.5	٧	
	Start up Time				10	ms	
	Phase Noise (Typical)	10 Hz	100 Hz	1 kHz	10 kHz	100 kHz	Offset from carrier
		-65	-95	-120	-140	-150	
	Temperature Cycle	MIL-STD-883, Method 1010, Condition B					125°C; Air-toAir; ; 10 min. dwell
	Mechanical Shock	MIL-STD-883, Method 2002, Condition B				1500 g's	
=	Vibration	MIL-STD-883, Method 2007, Condition B				20-2000 Hz; 0.06 inch; 15 g's; 3 planes	
enta	Humidity Steady State	MIL-STD-202, Method 103				40°C; 90%-95% R.H.; 56 days	
Ē	Thermal Shock	MIL-STD-883, Method 1011.7, Cond. B				100°C to 0°C; Water-to-Water; 15 cycles	
Environmental	Electrostatic Discharge	MIL-STD-883, Method 3015, Class II				2 KV to 4 KV Threshold	
En	Solderability	MIL-STD-883, Method 2022.2				Solder dip; Meniscograph Criteria	
	Hermeticity	MIL-STD-883, Method 1014.8, Cond. A1				Mass spectro. 2 x 10-8 atoms. CC/sec He	
	Resistance to Soldering	See Page 147					
	Lead Integrity	MIL-STD-883, Mtd. 2004.5, Cond. A,B1				Lead tension & bend stress	
	Marking Permanence	MIL-STD-883, Method 2015.8				Resistance to solvents	
	Life Test	MIL-STD-883, Method 1005.6				125°C, powered, 1000 hours minimum	

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